Product data sheet

1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and Pressfit type. Integrated with NTC temperature sensor.



2. Features and benefits

- · H Bridge topology
- · Press-fit pin type
- Low R_{DSon}
- Low Switching Losses
- Low Q_g and C_{rss}
- Low Inductive Design

3. Applications

- · Power inverters
- AC-DC converters
- · Active power factor correctors
- Motor drives

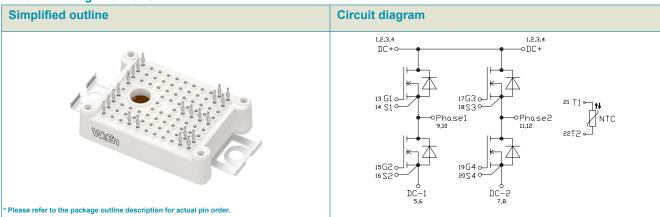
4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values			Unit		
Absolute maximum rating									
V _{DS}	drain-source voltage	T _j = 25 °C			1200		V		
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			38		Α		
P _{tot}	total power dissipation	T _h = 25 °C			74		W		
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit		
Static ch	aracteristics								
R _{DS(on)}	drain-source on-state	$V_{GS} = 15 \text{ V}; I_D = 33 \text{ A}; T_j = 25 \text{ °C}$		-	40	-	mΩ		
	resistance	V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ		
Dynamic	characteristics								
Q _{G(tot)}	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	115	-	nC		
Q_{GD}	gate-drain charge	T _j = 25 °C		-	18	-	nC		
Source-drain diode									
Q _r	recovered charge	I_{SD} = 33 A; V_{GS} = -4 V/18 V; V_{R} = 600 V; di/dt = 3400 A/µs; $R_{G(ext)}$ = 5.1 Ω ; T_{j} = 25 °C		-	465	-	nC		

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	•	Package issue date
WMSC040F12B1P-B	WeEnPACK-B1	WMSC040F12B1P-B6T	Tray	24	WeEnPACK- B1PFB-B	20-Mar-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC040F12B1P-B	WMSC040F12B1P-B

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

$T_{j,op} \qquad \text{operating junction temperature} \qquad \qquad -40 \text{ to } 150 \qquad ^{\circ}$ $T_{j,max} \qquad \text{maximum junction temperature} \qquad \qquad \text{Intermittent condition with shortened} \qquad -40 \text{ to } 175 \qquad ^{\circ}$ $V_{ISOL} \qquad \text{RMS isolation voltage} \qquad T_{j} = 25 ^{\circ}\text{C; all terminals shorted;} \qquad 3500 \qquad ^{\circ}$ $MOSFET$ $V_{DS} \qquad \text{drain-source voltage} \qquad T_{j} = 25 ^{\circ}\text{C}$ $V_{GS,max} \qquad \text{gate-source voltage} \qquad \text{Absolute maximum values} \qquad -12 \text{ to } 24 \qquad ^{\circ}$ $V_{GS,op} \qquad \text{gate-source voltage} \qquad \text{Recommended operational values} \qquad -4 \text{ to } 18 \qquad ^{\circ}$ $V_{DS} \qquad \text{drain current} \qquad V_{CS} = 18 \text{V; } T_{h} = 25 ^{\circ}\text{C} \qquad 38 \qquad ^{\circ}$ $V_{GS,op} \qquad \text{gate-source voltage} \qquad \text{Recommended operational values} \qquad -4 \text{ to } 18 \qquad ^{\circ}$ $V_{CS} = 18 \text{V; } T_{h} = 25 ^{\circ}\text{C} \qquad 38 \qquad ^{\circ}$ $V_{CS} = 18 \text{V; } T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{DM} \qquad \text{peak drain current} \qquad \text{pulse width tp limited by } T_{Jmax} \qquad 80 \qquad ^{\circ}$ $V_{DS} = 18 \text{V; } T_{J(Jmit)} = 25 ^{\circ}\text{C; per MOSFET} \qquad 288 \qquad \text{produce avalanche} \qquad -288 \text{produce of the source avalanche} \qquad -288 produce of the source of the sourc$	Symbol	Parameter	Conditions	Notes	Values	Unit
$T_{j,max} \qquad \text{maximum junction temperature} \qquad \text{Intermittent condition with shortened} \qquad -40 \text{ to } 175 \qquad ^{\circ}$ $V_{ISOL} \qquad \text{RMS isolation voltage} \qquad T_{j} = 25 ^{\circ}\text{C}; \text{ all terminals shorted}; \qquad 3500 \qquad ^{\circ}$ $MOSFET$ $V_{DS} \qquad \text{drain-source voltage} \qquad T_{j} = 25 ^{\circ}\text{C} \qquad 1200 \qquad ^{\circ}$ $V_{GS,max} \qquad \text{gate-source voltage} \qquad \text{Absolute maximum values} \qquad -12 \text{ to } 24 \qquad ^{\circ}$ $V_{GS,op} \qquad \text{gate-source voltage} \qquad \text{Recommended operational values} \qquad -4 \text{ to } 18 \qquad ^{\circ}$ $V_{DS} \qquad \text{drain current} \qquad V_{GS} = 18 \text{V}; T_{h} = 25 ^{\circ}\text{C} \qquad 74 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 38 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 100 ^{\circ}\text{C} \qquad 24 \qquad ^{\circ}$ $V_{GS} = 18 \text{V}; T_{h} = 25 ^{\circ}\text{C}; \text{ per MOSFET} \qquad 288 \qquad results of the properties of the prop$	T_{stg}	storage temperature			-40 to 125	°C
Ilifetime Ili	$T_{j.op}$	operating junction temperature			-40 to 150	°C
$ \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	$T_{j.max}$	maximum junction temperature			-40 to 175	°C
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	V _{ISOL}	RMS isolation voltage			3500	V
$V_{\text{GS,max}} \text{gate-source voltage} \qquad \text{Absolute maximum values} \qquad -12 \text{ to } 24 \qquad \text{V}$ $V_{\text{GS,op}} \text{gate-source voltage} \qquad \text{Recommended operational values} \qquad -4 \text{ to } 18 \qquad \text{V}$ $P_{\text{tot}} \text{total power dissipation} \qquad T_h = 25 ^{\circ}\text{C} \qquad \qquad 74 \qquad \text{V}$ $I_D \text{drain current} \qquad V_{\text{GS}} = 18 \text{V}; T_h = 25 ^{\circ}\text{C} \qquad \qquad 38 \qquad A \qquad $	MOSFET					
$\begin{array}{c} V_{\text{GS,op}} & \text{gate-source voltage} & \text{Recommended operational values} & -4 \text{ to } 18 & \text{V} \\ P_{\text{tot}} & \text{total power dissipation} & T_{\text{h}} = 25 ^{\circ}\text{C} & 74 & \text{V} \\ I_{\text{D}} & \text{drain current} & V_{\text{GS}} = 18 \text{V; } T_{\text{h}} = 25 ^{\circ}\text{C} & 38 & \text{A} \\ \hline V_{\text{GS}} = 18 \text{V; } T_{\text{h}} = 100 ^{\circ}\text{C} & 24 & \text{A} \\ \hline I_{\text{DM}} & \text{peak drain current} & \text{pulse width tp limited by } T_{\text{jmax}} & 80 & \text{A} \\ \hline E_{\text{as}} & \text{single pulse drain-to-source avalanche} & I_{\text{AS}} = 24 \text{A; L} = 1 \text{mH; V}_{\text{DD}} = 100 \text{V;} \\ \hline T_{\text{j(init)}} = 25 ^{\circ}\text{C; per MOSFET} & 288 & \text{recommended operational values} \\ \hline \textbf{Body Diode} & & & & & & & & & & & & & & & & & & &$	V_{DS}	drain-source voltage	T _j = 25 °C		1200	V
$P_{tot} \qquad \text{total power dissipation} \qquad T_h = 25 ^{\circ}\text{C} \qquad \qquad 74 \qquad \text{N}$ $I_D \qquad \text{drain current} \qquad V_{GS} = 18 \text{V}; T_h = 25 ^{\circ}\text{C} \qquad \qquad 38 \qquad \text{A}$ $V_{GS} = 18 \text{V}; T_h = 100 ^{\circ}\text{C} \qquad \qquad 24 \qquad \text{A}$ $I_{DM} \qquad \text{peak drain current} \qquad \text{pulse width tp limited by } T_{jmax} \qquad \qquad 80 \qquad \text{A}$ $E_{as} \qquad \text{single pulse drain-to-} \qquad I_{AS} = 24 \text{A}; L = 1 \text{mH; } V_{DD} = 100 \text{V}; \qquad \qquad 288 \qquad \text{r}$ $T_{j(init)} = 25 ^{\circ}\text{C}; \text{per MOSFET} \qquad \qquad \qquad 288 \qquad \text{r}$ $E_{DM} \qquad DC \text{ body diode forward current} \qquad T_h = 25 ^{\circ}\text{C}; V_{GS} = -4 \text{V} \qquad \qquad 18 \qquad \text{A}$	$V_{\rm GS,max}$	gate-source voltage	Absolute maximum values		-12 to 24	V
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$V_{\rm GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
$V_{GS} = 18 \text{ V; } T_h = 100 \text{ °C}$ I_{DM} peak drain current pulse width tp limited by T_{jmax} E_{as} single pulse drain-to- source avalanche $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } per \text{ MOSFET}$ I_{SD} DC body diode forward current $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } per \text{ MOSFET}$ I_{SD} DC body diode forward current $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $T_{j(init)} = 25 \text{ °C; } V_{GS} = -4 \text{ V}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = 1 \text{ mH; } V_{DD} = 100 \text{ V;}$ $I_{AS} = 24 \text{ A; } L = $	P _{tot}	total power dissipation	T _h = 25 °C		74	W
I_{DM} peak drain current pulse width tp limited by T_{jmax} 80 A E_{as} single pulse drain-to-source avalanche $I_{AS} = 24 \text{ A}$; $L = 1 \text{ mH}$; $V_{DD} = 100 \text{ V}$; $T_{j(init)} = 25 \text{ °C}$; per MOSFET 288 r Body Diode I_{SD} DC body diode forward current $T_h = 25 \text{ °C}$; $V_{GS} = -4 \text{ V}$ 18 A	I _D	drain current	V _{GS} = 18 V; T _h = 25 °C		38	Α
			V _{GS} = 18 V; T _h = 100 °C		24	Α
Body Diode I_{SD} DC body diode forward current $I_h = 25$ °C; per MOSFET 18	$I_{\rm DM}$	peak drain current	pulse width tp limited by T _{jmax}		80	Α
I_{SD} DC body diode forward current $I_h = 25 ^{\circ}\text{C}$; $V_{GS} = -4 ^{\circ}\text{V}$ 18	E _{as}				288	mJ
	Body Dioc	le				
I _{SD,pulse} Pulse body diode current verified by design, tp limited by T _{imax} 80 A	I _{SD}	DC body diode forward current	$T_h = 25 ^{\circ}C; V_{GS} = -4 V$		18	Α
	I _{SD,pulse}	Pulse body diode current	verified by design, tp limited by T_{jmax}		80	Α

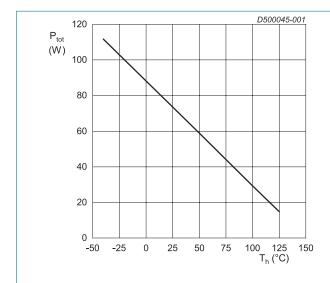


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

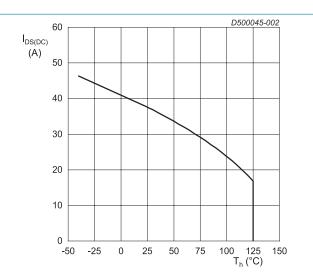


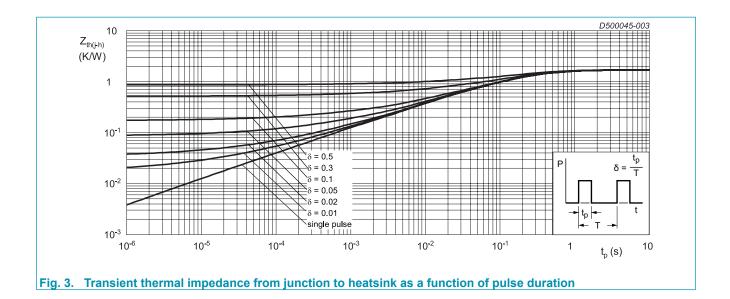
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
$R_{\text{th(j-c)}}$	thermal resistance from junction to case	per MOSFET		-	0.75	-	K/W
$R_{\text{th(j-h)}}$	thermal resistance from junction to heatsink	per MOSFET, λ_{grease} = 3 W/(m·K), thick _{grease} = 50 um		-	1.7	-	K/W
Internal Is	solation	basic insulation (class 1, IEC 61140)			Al_2O_3		
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
CTI	Comperative tracking index				>200		
F	Mounting force per clamp			20	-	50	N
G	Approximate Weight			-	20	-	g

Note: Module is ESD sensitive. Handling precautions are recommended.

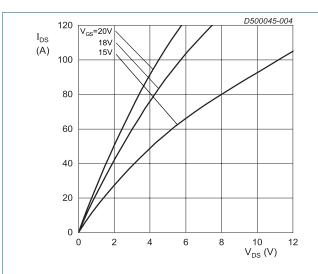


10. Characteristics

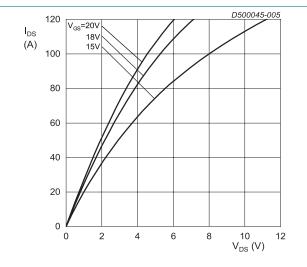
Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
	aracteristics				-71		
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 100 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C}$		1200	-	-	V
$V_{GS(th)}$	gate-source threshold	$I_D = 20 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$		1.9	2.6	3.5	V
	voltage	I _D = 20 mA; V _{DS} = V _{GS} ; T _j = 175 °C		-	1.9	-	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	0.2	100	μΑ
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 33 A; T _j = 25 °C		-	40	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 125 °C		-	46	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 150 °C		-	51	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 175 °C		-	54	-	mΩ
R_{G}	gate resistance	f = 1 MHz; T _j = 25 °C; per MOSFET		-	1	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 33 A; T _j = 25 °C		-	20	-	S
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	115	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	47	-	nC
Q_{GD}	gate-drain charge			-	18	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 100 KHz;		-	2.45	-	nF
C _{oss}	output capacitance	$T_j = 25 ^{\circ}\text{C}$		-	108	-	pF
C _{rss}	reverse transfer capacitance			-	11	-	pF
E _{oss}	Coss stored energy			-	54	-	μJ
$t_{d(on)}$	turn-on delay time	V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	27	-	ns
t _r	rise time	$R_{G(ext)} = 5.1 \Omega$; $I_D = 33 A$; $L = 300 \mu H$; $I_j = 25 °C$		-	30	-	ns
$t_{d(off)}$	turn-off delay time	,		-	42	-	ns
t _f	fall time			-	11	-	ns
E _{on}	turn-on energy			-	612	-	μJ
E _{off}	turn-off energy	1		_	90	_	μJ

Body dic	ode						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics		,				
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V}; I_{SD} = 33 \text{ A}; T_j = 25 \text{ °C}$		-	5.5	-	V
		V_{GS} = -4 V; I_{SD} = 33 A; T_j = 150 °C		-	5.0	-	V
Dynamic	characteristics					•	
I _{rrm}	reverse recovery current	$I_{SD} = 33 \text{ A}; V_{GS} = -4 \text{ V}/18 \text{ V}; V_{R} = 600 \text{ V};$		-	44	-	Α
t _{rr}	reverse recovery time	di/dt = 3400 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_i = 25 °C		-	19	-	ns
Q _r	recovered charge	1		-	465	-	nC
E _{rec}	reverse recovery energy			-	117	-	μJ
NTC ther	mistor		'				
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C			465±5%)	Ω
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	S

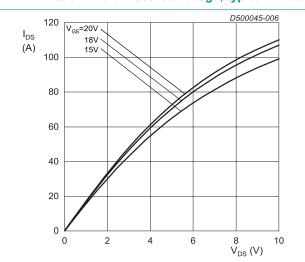


T_j = -40 °C; t_p < 200 μs Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

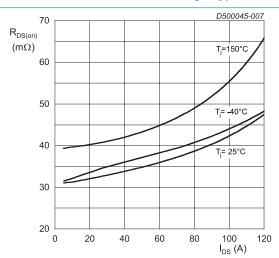


 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

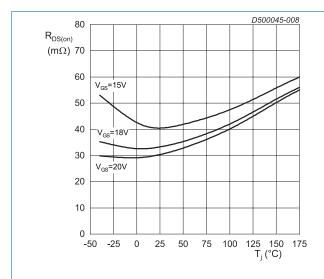
Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



 $T_j = 150~^{\circ}\text{C}; \ t_p < 200~\mu\text{s}$ Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

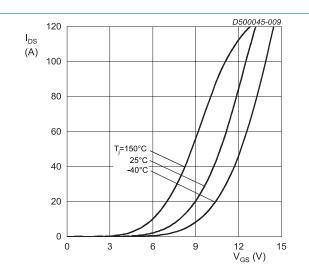


 $V_{\text{GS}} = 18 \text{ V; } t_{\text{p}} < 200 \text{ } \mu\text{s}$ Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



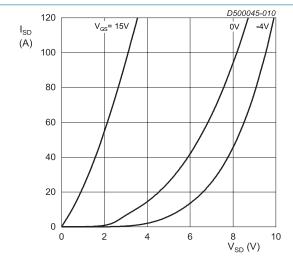
 I_{DS} = 33 A; t_p < 200 μ s

Fig. 8. Drain-source on-state resistance as a function of junction temperature



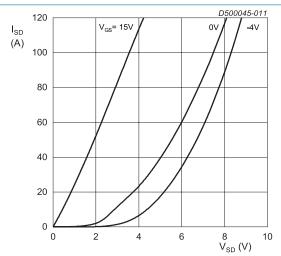
 $V_{DS} = 20 \text{ V}; t_p < 200 \text{ }\mu\text{s}$

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



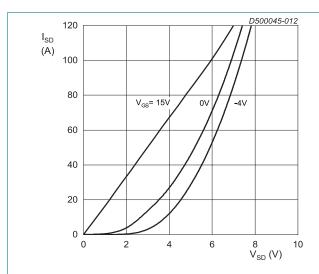
 T_j = -40 °C; t_p < 200 μ s

Fig. 10. Body diode forward characteristics; typical values

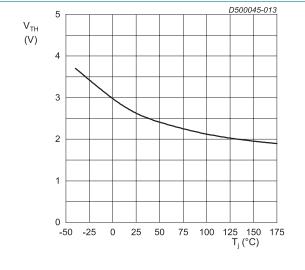


 $T_i = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

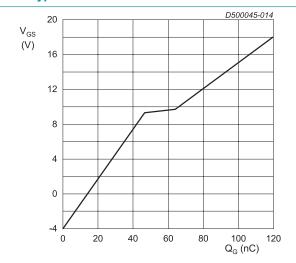
Fig. 11. Body diode forward characteristics; typical values



T_j = 150 °C; t_p < 200 μs Fig. 12. Body diode forward characteristics; typical values



V_{DS} = 10 V; I_{DS} = 10 mA Fig. 13. Threshold voltage as a function of junction temperature



I_{DS} = 33 A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values

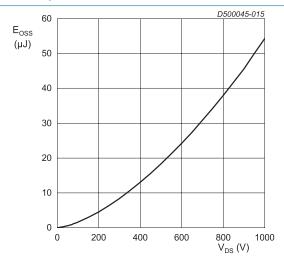
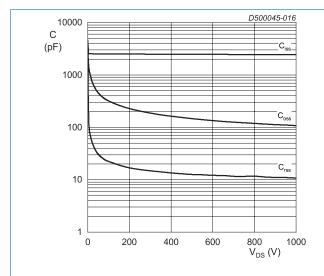
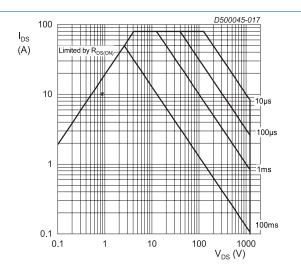


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



 $V_{DS} = 0 - 1000 V$

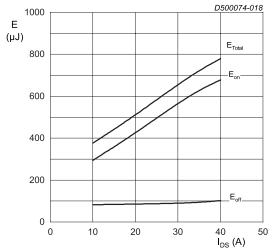
 $T_i = 25 \, ^{\circ}\text{C}; \, V_{AC} = 25 \, \text{mV}; \, f = 100 \, \text{KHz}$



 $T_i = 25 \,^{\circ}C; D = 0$ Parameter: t_p

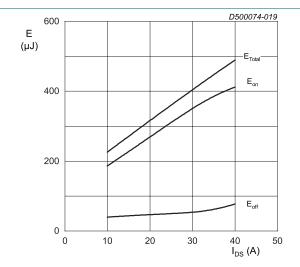
Fig. 16. Input, output and reverse transfer capacitances Fig. 17. Forward bias safe operating area as a function of drain-source voltage; typical





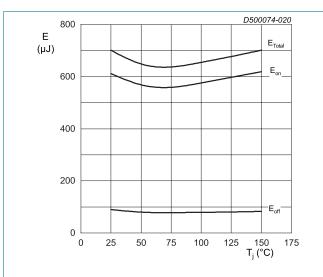
 T_{j} = 25 °C; V_{DD} = 800 V; $R_{G(ext)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



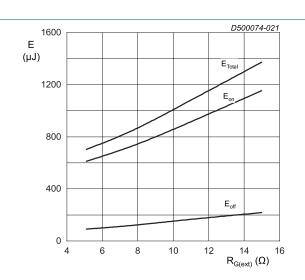
 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



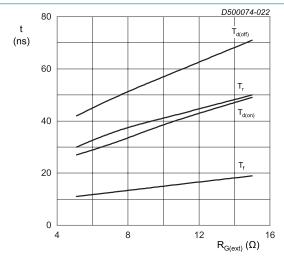
 $I_{DS}=33$ A; $V_{DD}=800$ V; $R_{G(off)}=5.1$ $\Omega;$ $R_{G(on)}=5.1$ $\Omega;$ $V_{GS}=$ -4 V/18 V; $L=300~\mu H$

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 T_{j} = 25 °C; V_{DD} = 800 V; I_{DS} = 33 A; V_{GS} = -4 V/18 V; L = 300 μH

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 $T_{\rm j}$ = 25 °C; $V_{\rm DD}$ = 800 V; $I_{\rm DS}$ = 33 A; $V_{\rm GS}$ = -4 V/18 V; L = 300 μH

Fig. 22. Switching time as a function of external gate resistance

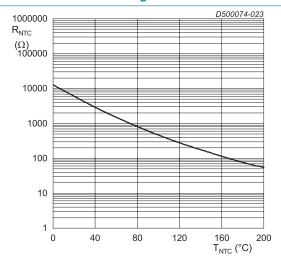
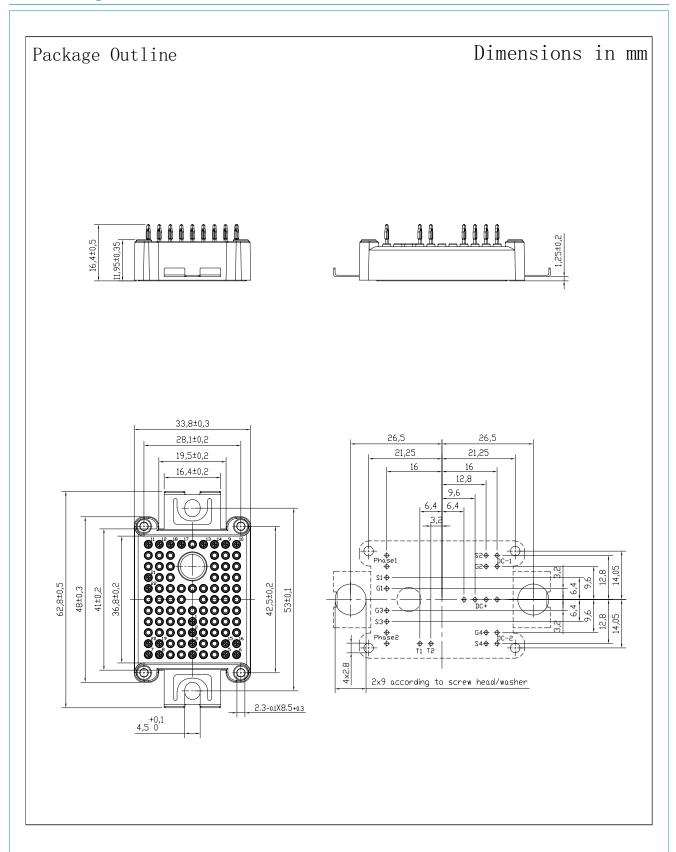


Fig. 23. NTC thermistor resistance as a function of NTC temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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- [2] The term 'short data sheet' is explained in section "Definitions".
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Date of release: 01 March 2025

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